IN THE SPECIFICATION

In the amendment filed with the present continuation application in which

continuation data was inserted before the first line of page 1 of the specification,

after "April 4, 1995", please insert --now U. S. Patent No. 5,560,244--, and after

"August 17, 1993" insert --now U. S. Patent No. 5,463,897--.

Page 2, line 17, before "entitled" insert --now U. S. Patent No. 5,412,980--.

Page 2, line 23, change "53(12), Sep. 19, 1988)" to --65, 1 January

1989)--.

Page 4, line 13, change "Mayer" to --Meyer--;

Page 4, line 15, change "1989" to --1991--.

Page 9, line 23, after "08/009,076" insert --now U. S. Patent No.

5,266,801--.

Page 14, line 23, change "4" to --4A--.

Page 16, line 5, change "4" to --4A--.

Page 16, line 23, change "4" to --4A--.

Page 18, line 7, after "beam" insert --47--; same line, change "47" to --48--.

Page 22, lines 15 and 17, change "44" to --68--.

Page 25, line 22, after "beam" insert --91--.

Page 26, line 9, after "motion." insert --The beam 92 reflected from

A50\digital-prater.amd

β1   cantilever 14 is detected by position sensitive detector 16.--

Page 29, line 18, after "source" insert --100--.

Page 31, line 22, change "4" to --4A--.

Page 32, line 6, change "4" to --4A--.

Page 32, line 7, change "48" to --42 (Fig. 4B)--.

Page 33, line 9, delete "the" (the second occurrence);

Page 33, line 20, after "08/009,076" insert --now U. S. Patent No.

5,266,801--.

IN THE CLAIMS

Please cancel claims 1-41.

Please add the following new claims 42-77 as follows:

--42.   An atomic force microscope including an optical lever system,

comprising:

a scanning mechanism;

an optical lever system including a light source not moved by said

*β2
cont'd*   scanning mechanism;

a cantilever moved by said scanning mechanism so that said cantilever

may be scanned over a sample;

a position detector not moved by said scanning mechanism which